Masahiro Aoyagi

List of Publications by Year in descending order

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#	Article	IF	CITATIONS
1	A Robust Two-axis Tilt Angle Sensor Based on Air/Liquid Two-phase Dielectric Capacitive Sensing Structure. IETE Journal of Research, 2020, 66, 685-696.	2.6	5
2	Material effect on thermal stress of annular-trench-isolated through silicon via (TSV). Japanese Journal of Applied Physics, 2020, 59, SLLH01.	1.5	3
3	Fabrication and stacking of through-silicon-via array chip formed by notchless Si etching and wet cleaning of first metal layer. Japanese Journal of Applied Physics, 2019, 58, SDDL09.	1.5	1
4	Hardness Characteristics of Au Cone-Shaped Bumps Targeted for 3-D Packaging Applications. IEEE Transactions on Components, Packaging and Manufacturing Technology, 2019, 9, 419-426.	2.5	1
5	Stress investigation of annular-trench-isolated TSV by polarized Raman spectroscopy measurement and finite element simulation. Microelectronics Reliability, 2019, 99, 125-131.	1.7	8
6	Thermal Stress Comparison of Annular-Trench-Isolated (ATI) TSV with Cu and Solder Core. , 2019, , .		3
7	Cool Interconnect: A 1024-bit Wide Bus for Chip-to-Chip Communications in 3-D Integrated Circuits. IEEE Transactions on Components, Packaging and Manufacturing Technology, 2019, 9, 525-535.	2.5	4
8	3D IC Stacking Technology for Reducing Power Consumption of Logic LSI System. Journal of Japan Institute of Electronics Packaging, 2019, 22, 374-379.	0.1	0
9	Investigation of transient thermal dissipation in thinned LSI for advanced packaging. Japanese Journal of Applied Physics, 2018, 57, 04FC06.	1.5	Ο
10	Fluidic platform with embedded differential capacitively coupled contactless conductivity detector for micro-object sensing. International Journal of Nanotechnology, 2018, 15, 24.	0.2	8
11	Evaluation of substrate noise suppression method to mitigate crosstalk among trough-silicon vias. Japanese Journal of Applied Physics, 2018, 57, 04FC07.	1.5	2
12	Residual stress investigation of via-last through-silicon via by polarized Raman spectroscopy measurement and finite element simulation. Japanese Journal of Applied Physics, 2018, 57, 07MF02.	1.5	9
13	Fine Cone-shaped Bumps for Three-dimensional LSI Package—An Optimization of Thermocompression Bonding Process. Sensors and Materials, 2018, 30, 2905.	0.5	4
14	Thermal impact of extreme die thinning in bump-bonded three-dimensional integrated circuits. Microelectronics Reliability, 2017, 79, 380-386.	1.7	1
15	Metal Contamination Evaluation of Via-Last Cu TSV Process Using Notchless Si Etching and Wet Cleaning of the First Metal Layer. , 2017, , .		Ο
16	30-GHz High-Frequency Application of Screen Printed Interconnects on an Organic Substrate. IEEE Transactions on Components, Packaging and Manufacturing Technology, 2017, 7, 1506-1515.	2.5	6
17	Coplanar differential capacitively coupled contactless conductivity detection (CD-C4D) sensor for micro object inside fluidic flow recognization. , 2017, , .		1
18	Development of a high-yield via-last through silicon via process using notchless silicon etching and wet cleaning of the first metal layer. Japanese Journal of Applied Physics, 2017, 56, 07KE02.	1.5	10

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19	Wet cleaning process for high-yield via-last TSV formation. , 2016, , .		2
20	Improvement of a TSV Reveal Process Comprising Direct Si/Cu Grinding and Residual Metal Removal. , 2016, , .		5
21	High frequency performance characterization of super-fine inkjet printed silver traces. , 2016, , .		Ο
22	Low Residual Stress in Si Substrate of Annular-Trench-Isolated TSV. , 2016, , .		4
23	Integration of a microfluidic chip with multiplexed optical fluorescence detector through anisotropic etching of Si using Tetramethylammonium hydroxide (TMAH). , 2016, , .		0
24	Two-axis tilt angle detection based on dielectric liquid capacitive sensor. , 2016, , .		5
25	Fabrication and stress analysis of annular-trench-isolated TSV. Microelectronics Reliability, 2016, 63, 142-147.	1.7	12
26	Impact of thinning stacked dies on the thermal resistance of bump-bonded three-dimensional integrated circuits. Microelectronics Reliability, 2016, 67, 2-8.	1.7	2
27	A Prospective Low-k Insulator for Via-Last through-Silicon-Vias (TSVs) in 3D Integration. , 2016, , .		Ο
28	Fabrication of superconducting tunnel junctions with embedded coil for applying magnetic field. Physica C: Superconductivity and Its Applications, 2016, 530, 90-92.	1.2	1
29	Validation of TSV thermo-mechanical simulation by stress measurement. Microelectronics Reliability, 2016, 59, 95-101.	1.7	13
30	Copper-Filled Through-Silicon Vias With Parylene-HT Liner. IEEE Transactions on Components, Packaging and Manufacturing Technology, 2016, 6, 510-517.	2.5	9
31	Investigation of metal contamination induced by a through silicon via reveal process using direct Si/Cu grinding and residual metal removal. Japanese Journal of Applied Physics, 2016, 55, 06GP06.	1.5	1
32	High-speed optical three dimensional measurement method for micro bump inspection in 3D LSI chip stacking technology. , 2015, , .		1
33	Impact of die thinning on the thermal performance of a central TSV bus in a 3D stacked circuit. Microelectronics Journal, 2015, 46, 1106-1113.	2.0	12
34	A method enabling height-control of chips for edge-emitting laser stacking. Japanese Journal of Applied Physics, 2015, 54, 04DB02.	1.5	0
35	Investigation of effects of metalization on heat spreading in bump-bonded 3D systems. , 2015, ,		0
36	Sensitivity of the thermal profile of bump-bonded 3D systems to inter-die bonding layer properties. ,		1

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37	Guard-ring monitoring system for inspecting defects in TSV-based data buses. , 2015, , .		1
38	Twice-etched silicon approach for via-last through-silicon-via with a Parylene-HT liner. , 2015, , .		2
39	Investigation into the thermal effects of thinning stacked dies in three-dimensional integrated circuits. , 2015, , .		3
40	Methods to reduce thermal stress for TSV Scaling $\hat{a}^{1}/4$ TSV with novel structure: Annular-Trench-Isolated TSV. , 2015, , .		10
41	Metal contamination evaluation of a TSV reveal process using direct Si/Cu grinding and residual metal removal. , 2015, , .		7
42	Novel through silicon via exposure process comprising Si/Cu grinding, electroless Ni–B plating, and wet etching of Si. Japanese Journal of Applied Physics, 2014, 53, 05GE02.	1.5	7
43	Fabrication and electrical characterization of Parylene-HT liner bottom-up copper filled through silicon via (TSV). , 2014, , .		10
44	Substrate monitoring system for inspecting defects in TSV-based data buses. , 2014, , .		0
45	Ultrawideband ultralow PDN impedance of decoupling capacitor embedded interposers using narrow gap chip parts mounting technology for 3-D integrated LSI system. , 2014, , .		3
46	Investigation of effects of die thinning on central TSV bus driver thermal performance. , 2014, , .		3
47	Analysis of thermal stress distribution for TSV with novel structure. , 2014, , .		10
48	Copper filled TSV formation with Parylene-HT insulator for low-temperature compatible 3D integration. , 2014, , .		2
49	Investigation of low-temperature deposition high-uniformity coverage Parylene-HT as a dielectric layer for 3D interconnection. , 2014, , .		15
50	Fine-pitch probing on TSVs and microbumps using a chip prober having a transparent membrane probe card. , 2014, , .		4
51	Method for back-annotating per-transistor power values onto 3DIC layouts to enable detailed thermal analysis. , 2014, , .		3
52	15-µm-pitch Cu/Au interconnections relied on self-aligned low-temperature thermosonic flip-chip bonding technique for advanced chip stacking applications. Japanese Journal of Applied Physics, 2014, 53, 04EB04.	1.5	10
53	High-precision integration approach based on alignment maintaining flip-chip bonding using cone shaped bump and truncated pyramid pad. , 2014, , .		1
54	Fabrication of a membrane probe card using transparent film for three-dimensional integrated circuit testing. Japanese Journal of Applied Physics, 2014, 53, 06JM06.	1.5	4

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55	Damage Evaluation of Wet-Chemical Si-Wafer Thinning/Backside Via Exposure Process. IEEE Transactions on Components, Packaging and Manufacturing Technology, 2014, 4, 741-747.	2.5	7
56	Flip-chip bonding alignment accuracy enhancement using self-aligned interconnection elements to realize low-temperature construction of ultrafine-pitch copper bump interconnections. , 2014, , .		7
57	3D IC testing using a chip prober and a transparent membrane probe card. , 2014, , .		2
58	Basic evaluation of Au micro-bumps formed by cyanide-free electroless Au plating process. , 2014, , .		1
59	Small-diameter TSV reveal process using direct Si/Cu grinding and metal contamination removal. , 2014, , .		4
60	Wideband ultralow power distribution network impedance evaluation of decoupling capacitor embedded interposers for 3-D integrated LSI system. , 2013, , .		3
61	Modified thermosonic flip-chip bonding based on electroplated Cu microbumps and concave pads for high-precision low-temperature assembly applications. , 2013, , .		6
62	Development of Cu-less TSV reveal process using Si/Cu grinding, electroless Ni plating, and alkaline etching of Si. , 2013, , .		3
63	Development of a chip prober for pre-bond testing of a 3D-IC. , 2013, , .		5
64	Special session 4C: Hot topic 3D-IC design and test. , 2013, , .		0
65	Investigation of optimized high-density flip-chip interconnect design including micro Au bumps for 3-D stacked LSI packaging. , 2013, , .		1
66	High-Speed Alkaline Etching for Backside Exposure of Through Silicon Vias. ECS Transactions, 2013, 50, 39-48.	0.5	0
67	A novel method of hotspot temperature reduction for a 3D stacked CMOS IC chip device fabricated on an ultrathin substrate. Journal of Micromechanics and Microengineering, 2013, 23, 025020.	2.6	13
68	Investigation of a microchannel-based cooling interposer for high-performance memory-on-logic 3DIC design. , 2013, , .		0
69	Development of decoupling capacitor embedded interposers using narrow gap chip parts mounting technology with wideband ultralow PDN impedance. , 2013, , .		5
70	Thermal Conductive Properties of a Semiconductor Laser on a Polymer Interposer. Japanese Journal of Applied Physics, 2013, 52, 04CG05.	1.5	2
71	New optical three dimensional structure measurement method of cone shape micro bumps used for 3D LSI chip stacking. , 2013, , .		4
72	Sub-Micron-Accuracy Gold-to-Gold Interconnection Flip-Chip Bonding Approach for Electronics–Optics Heterogeneous Integration. Japanese Journal of Applied Physics, 2013, 52, 04CB08.	1.5	12

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73	Cool System scalable 3-D stacked heterogeneous Multi-Core / Multi-Chip architecture for ultra low-power digital TV applications. , 2012, , .		6
74	Development of damage-less wet-chemical silicon-wafer thinning process for three-dimensional integration. , 2012, , .		3
75	Wet-Chemical Silicon Wafer Thinning Process for High Chip Strength. ECS Transactions, 2012, 45, 141-150.	0.5	3
76	Hot spots suppression by high thermal conductivity film in thin-sub strate CMOS ICs for 3D integration. , 2012, , .		1
77	Ultralow impedance analysis and evaluation of power distribution network for decoupling capacitor embedded interposers of 3-D integrated LSI system. , 2012, , .		0
78	Investigation of optimized high-density flip-chip interconnect design including micro Au bumps and underfill for ultrabroadband (DC-40GHz) applications. , 2012, , .		1
79	Silicon wafer thinning and backside via exposure by wet etching. , 2012, , .		2
80	COOL interconnect low power interconnection technology for scalable 3D LSI design. , 2011, , .		9
81	Impact of joint materials on the reliability of double-side packaged SiC power devices during high temperature aging. Journal of Materials Science: Materials in Electronics, 2010, 21, 917-925.	2.2	9
82	Anisotropic Deposition of Localized Electroless Nickel for Preferential Bridge Connection. Journal of the Electrochemical Society, 2010, 157, D65.	2.9	5
83	Low-impedance evaluation of power distribution network for decoupling capacitor embedded interposers of 3-D integrated LSI system. , 2010, , .		16
84	SrTiO <inf>3</inf> thin film decoupling capacitors on Si interposers for 3D system integration. , 2009, , .		3
85	A method of "chemical flip-chip bonding" without loading and heating for ultra-fine chip-to-substrate interconnects. , 2009, , .		4
86	Low-Cost Optical Subassembly Using VCSEL Pre-Self-Aligned With Optical Fiber for Optical Interconnect Applications. Journal of Lightwave Technology, 2009, 27, 4516-4523.	4.6	12
87	Vertically Pluggable and Compact 10-Gb/s\$,imes,\$12-Channel Optical Modules With Anisotropic Conductive Film for Over 100-Gb/s Optical Interconnect Systems. Journal of Lightwave Technology, 2009, 27, 3249-3258.	4.6	7
88	Compliant bump technology for back-side illuminated CMOS image sensor. , 2009, , .		2
89	Low-impedance power distribution network of decoupling capacitor embedded interposers for 3-D integrated LSI system. , 2009, , .		4
90	A Novel Three-Dimensional Packaging Method for Al-Metalized SiC Power Devices. IEEE Transactions on Advanced Packaging, 2009, 32, 773-779.	1.6	4

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91	Ultralow impedance evaluation system of wideband frequency for power distribution network of decoupling capacitor embedded substrates. , 2009, , .		Ο
92	Title is missing!. Journal of Japan Institute of Electronics Packaging, 2009, 12, 606-615.	0.1	1
93	Formation of Au Microbump Arrays for Flip-Chip Bonding Using Electroless Au Deposition from a Non-Cyanide Plating Bath. Transactions of the Japan Institute of Electronics Packaging, 2009, 2, 109-115.	0.4	3
94	Self-Alignment of Optical Devices With Fiber for Low-Cost Optical Interconnect Modules. IEEE Photonics Technology Letters, 2008, 20, 193-195.	2.5	5
95	A Method of Fabricating Bump-Less Interconnects Applicable to Wafer-Scale Flip-Chip Bonding. , 2008, ,		3
96	Joint Reliability of Double-Side Packaged SiC Power Devices to a DBC Substrate with High Temperature Solders. , 2008, , .		5
97	High-density and Low-cost 10-Gbps x 12ch Optical Modules for High-end Optical Interconnect Applications. , 2008, , .		7
98	High optical coupling efficiency using 45°-ended fibre for low-height and low-cost optical interconnect modules. Electronics Letters, 2008, 44, 724.	1.0	5
99	Chemical flip-chip bonding method for fabricating 10MU.m-pad-pitch interconnect. IEICE Electronics Express, 2008, 5, 732-737.	0.8	3
100	A Study on Coupling Efficiency between VCSEL and 45°-angled mirror component for Low-cost and High-density 10Gbps/ch Optical Parallel Link Module. Conference Proceedings - Lasers and Electro-Optics Society Annual Meeting-LEOS, 2007, , .	0.0	4
101	Novel Flip-Chip Bonding Technology using Chemical Process. , 2007, , .		4
102	Interconnection of Micropad Electrodes by Controlled "Extraneous―Deposition of Electroless NiB Film. Electrochemical and Solid-State Letters, 2007, 10, D92.	2.2	10
103	Investigation of a Sic Module with a High Operating Temperature for Power Applications. , 2007, , .		7
104	A novel chip joint method for high temperature operated SiC power modules. , 2006, , .		4
105	Extracting dielectric constant of low-k thin film material for interposer of 3-D multilayer packaging. , 2006, , .		2
106	Synthesis of a Novel Poly(binaphthylene ether) Containing Trifluoromethyl Groups with a Low Dielectric Constant. Macromolecules, 2006, 39, 3964-3966.	4.8	51
107	Polyimide Buffer Layer for STJ Photon Detector. Journal of Physics: Conference Series, 2006, 43, 1319-1321.	0.4	1
108	Low-Cost and High-Density 10Gbps/ch Optical Parallel Link Module for Multi-Terabit Router		9

Application. , 2006, , .

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109	Band-Stop Filter Effect of Power/Ground Plane on Through-Hole Signal Via in Multilayer PCB. IEICE Transactions on Electronics, 2006, E89-C, 551-559.	0.6	8
110	Micropattern Formation of Photosensitive Imide Block Copolymer Thick Films. Journal of Photopolymer Science and Technology = [Fotoporima Konwakai Shi], 2005, 18, 301-306.	0.3	2
111	X-Ray Detection Using Superconducting Tunnel Junctions With Polyimide Insulation Layer. IEEE Transactions on Applied Superconductivity, 2005, 15, 606-608.	1.7	1
112	Double Relaxation Oscillation SQUID with a 4JL On-Chip Digital Flux Locked-Loop Circuit. IEEE Transactions on Applied Superconductivity, 2005, 15, 332-335.	1.7	5
113	Efficient Fabrication Process for Superconducting Integrated Circuits Using Photosensitive Polyimide Insulation Layers. IEEE Transactions on Applied Superconductivity, 2005, 15, 94-97.	1.7	4
114	New Fabrication Process for Superconducting Quantum Interference Devices With Nb/AlAlOx/Nb Junctions by Using Photosensitive Polyimide Insulation Layers. IEEE Transactions on Applied Superconductivity, 2005, 15, 825-828.	1.7	1
115	Fabrication of High-Density Wiring Interposer for 10 GHz 3D Packaging Using a Photosensitive Multiblock Copolymerized Polyimide. Japanese Journal of Applied Physics, 2004, 43, 4141-4145.	1.5	25
116	Precise high frequency measurement method without connectors for small diameter coaxial cable. , 2004, , .		0
117	High-Tc interferometers using all YBa2Cu3O7â^î^trilayer junctions. Applied Physics Letters, 2003, 83, 2390-2392.	3.3	Ο
118	A GHz multi-channel cryogenic test fixture for superconducting integrated circuit testing. IEEE Transactions on Applied Superconductivity, 2003, 13, 459-462.	1.7	5
119	New fabrication process for josephson tunnel junctions using photosensitive polyimide insulation layer for superconducting integrated circuits. IEEE Transactions on Applied Superconductivity, 2003, 13, 119-122.	1.7	8
120	X-ray detection by an on-chip coil integrated superconducting tunnel junction. Review of Scientific Instruments, 2003, 74, 3258-3262.	1.3	0
121	On-chip coil-integrated STJ using the persistent superconducting current for photon detectors. IEEE Transactions on Applied Superconductivity, 2003, 13, 1132-1138.	1.7	2
122	Response of an On-Chip Coil-Integrated Superconducting Tunnel Junction to X-rays. Japanese Journal of Applied Physics, 2003, 42, 2860-2863.	1.5	0
123	Superconducting ultrahigh-speed time domain reflectometry measurement system for electrical characterization of transmission line structures. Superconductor Science and Technology, 2003, 16, 1434-1437.	3.5	0
124	On-chip coil integrated superconducting tunnel junction for a high performance X-ray detector. Physica C: Superconductivity and Its Applications, 2002, 372-376, 403-406.	1.2	6
125	Interlayer dielectric process for LSI circuits using positive photosensitive polyimide synthesized by block-copolymerization. , 2001, , .		8
126	Detection of heavy ions using Nb-based superconducting tunnel junction. IEEE Transactions on Applied Superconductivity, 2001, 11, 712-715.	1.7	1

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127	A microstrip-coil integration on superconducting tunnel junctions for X-ray detection. IEEE Transactions on Applied Superconductivity, 2001, 11, 700-703.	1.7	4
128	Development of superconducting tunnel junctions for ultra soft X-ray detectors. IEEE Transactions on Applied Superconductivity, 2001, 11, 721-723.	1.7	6
129	A high-resolution X-ray detection system using STJ and SQUID amplifier. IEEE Transactions on Applied Superconductivity, 2001, 11, 704-707.	1.7	2
130	Precise patterning technique for Nb junctions using optical proximity correction. IEEE Transactions on Applied Superconductivity, 2001, 11, 381-384.	1.7	5
131	Spectral features of substrate phonon events obtained by illuminating superconducting tunnel junctions with X-rays. IEEE Transactions on Applied Superconductivity, 2001, 11, 708-711.	1.7	0
132	Properties of Substrate Phonon Events in Superconducting Tunnel Junctions Induced by X-Ray Absorption. Japanese Journal of Applied Physics, 2000, 39, 1710-1718.	1.5	6
133	Improved Fabrication Method for Nb/Al/AlOx/Al/Nb Superconducting Tunnel Junctions as X-Ray Detectors. Japanese Journal of Applied Physics, 2000, 39, 5090-5094.	1.5	27
134	NbN Superconducting Devices. , 2000, , .		0
135	Development of a compact system for high-resolution X-ray detection using a SQUID amplifier. IEEE Transactions on Applied Superconductivity, 1999, 9, 3858-3861.	1.7	0
136	Numerical studies of interchip pulse transmission for complex RSFQ systems. IEEE Transactions on Applied Superconductivity, 1999, 9, 3725-3728.	1.7	3
137	Development of superconducting tunnel junctions with an aluminum-oxide insulation layer for X-ray detection. IEEE Transactions on Applied Superconductivity, 1999, 9, 4475-4478.	1.7	11
138	An interface circuit for a Josephson-CMOS hybrid digital system. IEEE Transactions on Applied Superconductivity, 1999, 9, 3314-3317.	1.7	18
139	Fabrication of High Quality Superconducting Tunnel Junctions. Japanese Journal of Applied Physics, 1998, 37, 10.	1.5	0
140	Rapid single-flux-quantum dual-rail logic for asynchronous circuits. IEEE Transactions on Applied Superconductivity, 1997, 7, 2705-2708.	1.7	27
141	Noise and gain in frequency mixers with NbN SIS junctions. IEEE Transactions on Applied Superconductivity, 1997, 7, 1077-1080.	1.7	8
142	Fabrication process of superconducting integrated circuits with submicron Nb/AlO x /Nb junctions using electron-beam direct writing technique. , 1997, , .		2
143	Fabrication of submicron Nb/AlO/sub x//Nb Josephson junctions using ECR plasma etching technique. IEEE Transactions on Applied Superconductivity, 1997, 7, 2644-2648.	1.7	7
144	NbN-MgO-NbN junctions prepared on room-temperature quartz substrates for quasiparticle mixers. IEEE Transactions on Applied Superconductivity, 1997, 7, 2603-2606.	1.7	5

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145	Low noise submillimeter SIS receiver with niobium nitride quasiparticle tunnel junctions. Journal of Infrared, Millimeter and Terahertz Waves, 1996, 17, 1139-1147.	0.6	2
146	A niobiumnitride mixer with niobium tuning circuit. Applied Physics Letters, 1996, 69, 4102-4104.	3.3	6
147	A basic circuit for asynchronous superconductive logic using RSFQ gates. Superconductor Science and Technology, 1996, 9, A46-A49.	3.5	10
148	A Josephson built-in self-testing (JBIST) system for gigahertz functional tests of Josephson RAMs. Superconductor Science and Technology, 1996, 9, A50-A54.	3.5	0
149	<title>Noise properties of a mixer with SIS NbN quasi-particle tunnel junctions</title> . , 1995, , .		3
150	Specific capacitance of Nb/AlOx/Nb Josephson junctions with critical current densities in the range of 0.1–18 kA/cm2. Applied Physics Letters, 1995, 66, 2134-2136.	3.3	59
151	Subgap characteristics of Nb/AlOx/Nb tunnel junctions with high critical current density. IEEE Transactions on Applied Superconductivity, 1995, 5, 3073-3076.	1.7	8
152	An improved etching process used for the fabrication of submicron Nb/AlO/sub x//Nb Josephson junctions. IEEE Transactions on Applied Superconductivity, 1995, 5, 2334-2337.	1.7	6
153	Influence of a NbN overlayer on Nb/Al–AlOx/Nb high quality Josephson tunnel junctions for xâ€ray detection. Applied Physics Letters, 1995, 67, 3340-3342.	3.3	6
154	Fabrication of Small High-T c Trilayer Junctions Using Electron Beam Lithography. , 1995, , 1091-1094.		0
155	Observation of Josephson self-coupling inNbAlOxNbtunnel junctions. Physical Review B, 1994, 50, 9664-9667.	3.2	9
156	Antenna-coupled superconducting contacts in submillimeter and FIR astronomy. Infrared Physics and Technology, 1994, 35, 463-476.	2.9	6
157	Chip layout design of a Josephson LSI circuit for examining high-speed operability by using a standard cell automatic placement and routing technique. IEEE Transactions on Applied Superconductivity, 1994, 4, 169-176.	1.7	3
158	Josephson Junctions Consisting of all (103) Oriented YBaCuO/PrBaCuO/YBaCuO Trilayer Films. , 1994, , 1063-1066.		1
159	Design of a 16 kbit variable threshold Josephson RAM. IEEE Transactions on Applied Superconductivity, 1993, 3, 2675-2678.	1.7	0
160	Superconductor Wiring in Multichip Module for Josephson LSI Circuits. Japanese Journal of Applied Physics, 1993, 32, L898-L900.	1.5	12
161	Vortex phases and energy dissipation in narrow Nb strips: Reduction of collective pinning. Physical Review B, 1993, 47, 5481-5484.	3.2	12
162	Palladium Thin-Film Resistors for Josephson LSI Circuits. Japanese Journal of Applied Physics, 1992, 31, 2550-2553.	1.5	2

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163	Liquid-Nitrogen-Cooled Dry Etching of YBaCuO Thin Films. Japanese Journal of Applied Physics, 1992, 31, L1044-L1046.	1.5	34
164	NbN/MgO/NbN Josephson Junctions for Integrated Circuits. Japanese Journal of Applied Physics, 1992, 31, 1778-1783.	1.5	13
165	Submicron NbN/MgO/NbN Josephson tunnel junctions and their application to the logic circuit. IEEE Transactions on Applied Superconductivity, 1992, 2, 183-186.	1.7	9
166	A 4-bit Josephson computer ETL-JC1. IEEE Transactions on Applied Superconductivity, 1991, 1, 37-47.	1.7	32
167	A fully operational 1 kb variable threshold Josephson RAM. IEEE Journal of Solid-State Circuits, 1991, 26, 572-577.	5.4	15
168	Josephson computer technology. Endeavour, 1991, 15, 58-65.	0.4	0
169	Properties of Large-Sized Nb-Based Superconducting TunnelJunctions for X-Ray Detection. Japanese Journal of Applied Physics, 1991, 30, 1969-1974.	1.5	4
170	NbN Josephson junction with high critical current density for integrated circuits. Superconductor Science and Technology, 1991, 4, 626-628.	3.5	1
171	Fabrication process for Josephson computer ETL-JC1 using Nb tunnel junctions. IEEE Transactions on Magnetics, 1991, 27, 3109-3112.	2.1	16
172	A multichip superconducting microcomputer ETL-JC1. IEEE Transactions on Magnetics, 1991, 27, 2610-2617.	2.1	22
173	Josephson LSI fabrication technology using NbN/MgO/NbN tunnel junctions. IEEE Transactions on Magnetics, 1991, 27, 3180-3183.	2.1	11
174	A Josephson 10-b instruction 128-word ROM unit. IEEE Journal of Solid-State Circuits, 1990, 25, 971-978.	5.4	7
175	Josephson address control unit IC for a 4-bit microcomputer prototype. IEEE Transactions on Magnetics, 1989, 25, 789-794.	2.1	15
176	Submicron NbN Josephson tunnel junctions for digital applications. IEEE Transactions on Magnetics, 1989, 25, 1223-1226.	2.1	9
177	A 1 kbit Josephson random access memory using variable threshold cells. IEEE Journal of Solid-State Circuits, 1989, 24, 1034-1040.	5.4	34
178	A Josephson 4 bit RALU for a prototype computer. IEEE Journal of Solid-State Circuits, 1989, 24, 1076-1084.	5.4	20
179	Integrated DC–SQUID Magnetometer. Japanese Journal of Applied Physics, 1987, 26, 1050-1055.	1.5	19
180	Temperature-dependent properties of niobium nitride Josephson tunnel junctions. IEEE Transactions on Magnetics, 1987, 23, 1464-1471.	2.1	51

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181	PECVD SiO <inf>2</inf> film as a junction isolation for all refractory Josephson IC. IEEE Transactions on Magnetics, 1987, 23, 1389-1392.	2.1	11
182	Niobium Nitride Josephson Junctions with Double-Tunnel Barriers. Japanese Journal of Applied Physics, 1987, 26, 1611.	1.5	2
183	A 1 µm Cross-Line Junction Process. , 1986, , 557-563.		12
184	An integration of all refractory Josephson logic LSI circuit. IEEE Transactions on Magnetics, 1985, 21, 102-109.	2.1	48
185	Fabrication and performance of all refractory josephson logic circuits for 1 Kbit SFQ memory. IEEE Transactions on Magnetics, 1985, 21, 733-736.	2.1	5
186	Niobium nitride Josephson tunnel junctions with magnesium oxide barriers. Applied Physics Letters, 1985, 46, 1098-1100.	3.3	133
187	High quality Nb/Alâ€AlOx/Nb Josephson junction. Applied Physics Letters, 1985, 46, 1179-1181.	3.3	101
188	All Niobium Nitride Josephson Junction with Hydrogenated Amorphous Silicon Barrier and its Application to the Logic Circuit. Japanese Journal of Applied Physics, 1984, 23, L916-L918.	1.5	13
189	All refractory Josephson tunnel junctions fabricated by reactive ion etching. IEEE Transactions on Magnetics, 1983, 19, 827-830.	2.1	59
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